

*Docket Number:* 05–042. Applicant: Georgia Institute of Technology, 711 Marietta St., Atlanta, GA 30332. Instrument: Dual Beam SEM/FIB Electron Microscope System, Model Nova 200 Nanolab. Manufacturer: FEI Company, The Netherlands. Intended Use: The instrument is intended to be used to improve understanding of molecular mechanisms and functional assemblies, initiate development of new materials, and facilitate advances in environmental analysis and detection. New research and creative concepts will include: (1) multifunctional scanning nanoprobe and quantum cascade laser-based sensing systems, (2) stimulated surface chemistry using metal-insulator-metal (MIM) devices containing nano-scale field emission arrays, (3) optically gated single molecule transistors, (4) shape-preserving chemical conversion of 3-D bioclastic structures, (5) impedance mapping AFM cantilever arrays and (6) nanobelts as nanobiosensors, and nanocantilevers. Application accepted by Commissioner of Customs: September 15, 2005.

*Docket Number:* 05–043. Applicant: Massachusetts General Hospital, 55 Fruit Street, Boston, MA 02114. Instrument: Electron Microscope, Model JEM-1011. Manufacturer: JEOL Ltd., Japan. Intended Use: The instrument is intended to be used by the professional laboratory staff at Massachusetts General Hospital for the advancement of scientific knowledge relating to U.S. government funded medical research projects using electron microscopy, electron microtomy and ultracryomicrotomy techniques. Application accepted by Commissioner of Customs: September 12, 2005.

**Gerald A. Zerdy,**

*Program Manager, Statutory Import Programs Staff.*

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## DEPARTMENT OF COMMERCE

### International Trade Administration

#### **University of California, San Diego, et al., Notice of Consolidated Decision on Applications for Duty-Free Entry of Scientific Instruments**

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Suite 4100W, Franklin Court Building,

U.S. Department of Commerce, 1099 14th Street, NW, Washington, D.C.

*Comments:* None received. Decision: Approved. No instrument of equivalent scientific value to the foreign instruments described below, for such purposes as each is intended to be used, is being manufactured in the United States.

*Docket Number:* 05–038. Applicant: University of California, San Diego. Instrument: Low-Temperature Ultra-High Vacuum Scanning Tunneling Microscope. Manufacturer: Omicron NanoTechnology, GmbH, Germany. Intended Use: See notice at 70 FR 54366, September 14, 2005. Reasons: The foreign instrument provides: (1) a scanning tunneling microscope (STM) mounted inside a 4K liquid helium reservoir (8-hour time between liquid He refills), (2) operation at an equilibrium temperature of 4 K (including both tip and sample), (3) in-situ sample manipulation and tip transfer capabilities, (4) low drift rates of 1.0 angstrom/hour (5) RMS vibration amplitudes of <0.005 angstrom in a 300 Hz bandwidth and (6) sample surface facing downwards during STM imaging for easy dosing. Advice received from: A university research laboratory for advanced microstructures and devices.

*Docket Number:* 05–039. Applicant: University of Wisconsin, Eau Claire. Instrument: Automatic Fusion Machine, Model Autofluxer 4. Manufacturer: Breitlander, GmbH, Germany. Intended Use: See notice at 70 FR . Reasons: The foreign instrument provides dissolution of whole rock powder by a combination fusion/acid digestion for trace element analysis by ICP mass spectrometry. No apparatus of equivalent scientific value to the foreign apparatus, for such purposes as it is intended to be used, is being manufactured in the United States. This is a compatible accessory for an existing instrument purchased for the use of the applicant. The accessory is pertinent to the intended uses and we know of no domestic accessory which can be readily adapted for use with the existing instrument.

*Docket Number:* 05–040. Applicant: National Renewable Energy Laboratory, Golden, CO, 80401. Instrument: Dual Beam Focused Ion Beam Electron Microscope, Model Nova 200 NanoLab. Manufacturer: FEI Company, The Netherlands. Intended Use: See notice at 70 FR 54366, September 14, 2005. Reasons: The foreign instrument is an electron microscope and is intended for research or scientific educational uses requiring it. We know of no instrument suited to these purposes, which was being manufactured in the United States at the time of order of the instrument.

We know of no other instrument or apparatus being manufactured in the United States which is of equivalent scientific value to any of the foreign instruments.

**Gerald A. Zerdy,**

*Program Manager, Statutory Import Programs Staff.*

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**BILLING CODE 3510–DS–S**

## DEPARTMENT OF COMMERCE

### International Trade Administration

(A–570–803)

#### **Heavy Forged Hand Tools (i.e., Axes & Adzes, Bars & Wedges, Hammers & Sledges, and Picks & Mattocks) from the People's Republic of China: Final Results of the Expedited Sunset Review of the Antidumping Duty Orders**

**AGENCY:** Import Administration, International Trade Administration, Department of Commerce.

**SUMMARY:** On July 1, 2005, the Department of Commerce (“the Department”) initiated a sunset review of the antidumping duty (“AD”) orders on Heavy Forged Hand Tools (i.e., Axes & Adzes, Bars & Wedges, Hammers & Sledges, and Picks & Mattocks) (“HFHTs”) from the People’s Republic of China pursuant to section 751(c) of the Tariff Act of 1930, as amended (“the Act”). On the basis of notices of intent to participate and adequate substantive responses filed on behalf of the domestic interested parties and lack of response from respondent interested parties, the Department conducted an expedited sunset review of the AD orders pursuant to section 751(c)(3)(B) of the Act and section 351.218(e)(1)(ii)(C)(2) of the Department’s regulations. As a result of this sunset review, the Department finds that revocation of the AD orders would likely lead to continuation or recurrence of dumping at the levels indicated in the “Final Results of Review” section of this notice.

**EFFECTIVE DATE:** November 7, 2005.

**FOR FURTHER INFORMATION CONTACT:** Maureen Flannery, AD/CVD Operations, Import Administration, International Trade Administration, U.S. Department of Commerce, 14th Street and Constitution Avenue, NW, Washington, DC 20230; telephone: (202) 482–3020.

#### **SUPPLEMENTARY INFORMATION:**

##### **Background**

On July 1, 2005, the Department initiated a sunset review of the AD